

ION SLICED THIN FILMS

Partow's technology is based on crystal ion slicing of lithium niobate wafers. The process uses ion implantation to weaken the crystal bondage in a lithium niobate wafer. The implanted crystal is then bonded to a handle substrate and a thin layer of lithium niobate is transferred to the handle substrates using crystal ion slicing technique. A final chemical-mechanical polishing step smoothens the surface of the bonded thin film wafer. Currently, the company produces customized photonic thin film platforms using its thin film bonding system and can extend its process to provide more customized bonded platforms based on customer's needs and application.



Smart cut thin film lithium niobate on silicon product specification

X-cut lithium niobate single crystal on silicon dioxide on silicon Top lithium niobate layer Parameter Standard Custom Order Orientation X-cut X-cut, Y-cut or Z-cut Primary Flat (on LN film) +z TBD Secondary Flat (on LN film) -Y TBD Lithium Niobate Film Diameter 100 mm None Thickness 600 nm 300 − 1,000 nm Thickness Uniformity < 2% < 1% Surface Roughness < 1 nm < 1 nm				
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Surface Roughness < 1 nm < 1 nm				
Defective Area >100micron < 5% < 5%				
Defective Area <100micron < 1 per inch2 < 1 per inch2				
Intermediate SiO2 layer				
Parameter Standard Custom Order				

Part Number	LN-X-600-2000-100-100	LN-X-xxx-xxx-xx-100
Thickness Range	2,000 nm	0 nm – 6,000 nm
Thickness Uniformity	< 3%	< 3%
Silicon Substrate		
Parameter	Standard	Custom Order
Parameter Substrate Thickness	Standard 0.5 mm	Custom Order 0.5 – 1 mm